Abstracts

Characterization of Active and Passive Millimeter-Wave Monolithic Elements by On-Wafer Probing

G. Dawe and L. Raffaelli. "Characterization of Active and Passive Millimeter-Wave Monolithic Elements by On-Wafer Probing." 1989 MTT-S International Microwave Symposium Digest 89.1 (1989 Vol. I [MWSYM]): 413-415.

A Technique for modeling active and passive monolithic elements in a microstrip environment at millimeter wave frequencies using on-wafer probing is developed. This procedure involves accurately characterizing the coplanar waveguide to microstrip transition used in making on-wafer measurements. Once the transition is characterized, the models for various elements can be determined.

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